

Notice of References Cited	Application/Control No.	Applicant(s)/Patent Under Reexamination	
	10/071,881	HOSOKAWA ET AL.	
	Examiner Kalimah Fernandez	Art Unit 2881	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-			
	B	US-			
	C	US-			
	D	US-			
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FOREIGN PATENT DOCUMENTS

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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Danev et al, "Complex Observation in Electron Microscopy", Journal of Physical Society of Japan, vol. 70, no.3, Mar. 2001, pp. 669-702
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	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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